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1 Estimation of speed, area, and power of parameterizable, soft IP

Jagesh Sanghavi, Albert Wang

June 2001 **Proceedings of the 38th conference on Design automation**

Full text available: pdf(70.54 KB)

Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

We present a new approach to estimate speed, area, and power of a parameterizable, soft IP. By running the ASIC implementation flow only on selected configurations, we predict the performance for any arbitrary configuration. We exploit performance function decomposability to address the combinatorial explosion challenge. The estimator has been used successfully to configure Xtensa processor cores for numerous embedded SOC designs.

2 FSDS-Fairchild Software Development System

Harley Mathews, Kam Li, John Katsaros

January 1975 **Proceedings of the 1975 annual conference**

Full text available: pdf(382.72 KB)

Additional Information: [full citation](#), [abstract](#), [index terms](#)

The Fairchild F8 Software Development System (FSDS) runs on the Fairchild F8 Microprocessor. Designed to ease the burden of developing F8 based microprocessor systems, FSDS enables testing programs in a real world environment. The FSDS system provides for generating, editing and maintaining source files, assembling user's programs, and executing routines using F8 hardware. This system was developed both for in-house Fairchild applications as well as customer based development programs.

3 The Advanced Interactive Debugging System (AIDS)

Jolene J. Hart

December 1979 **ACM SIGPLAN Notices**, Volume 14 Issue 12

Full text available: pdf(1.36 MB)

Additional Information: [full citation](#), [abstract](#), [citations](#)

The Advanced Interactive Debugging System (AIDS) is described. It is a powerful high-level symbolic interactive debugging aid. AIDS is intended to be available in a program's environment without requiring debugging statements in the program's source code or inclusion of AIDS in the program's executable module.

4 OCM—a monitoring system for interoperable tools

Roland Wismüller, Jörg Trinitis, Thomas Ludwig

August 1998 **Proceedings of the SIGMETRICS symposium on Parallel and distributed tools**

Full text available: pdf(1.31 MB)

Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

5 A VHDL SGRGAM model for the validation environment of a high performance graphic processor

M. G. Wahl, H. Völkel

February 1998 **Proceedings of the conference on Design, automation and test in Europe**

Full text available:  [pdf\(115.05 KB\)](#)

Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

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To validate the functionality of a new highly complex graphics processor described in VHDL the working environment of the processors has to be modelled. In some cases appropriate models for the external components are commercially available, in other cases these models have to be created. In this paper a general memory model for SGRAMs is presented which had to be implemented to have a flexible simulation environment for a high speed graphics processor at hand. Key features are the generality, t ...

6 Display development system: a successful Ada application

Robin R. Miller, Mary Ann Dodge

March 1986 **Proceedings of the third annual Washington Ada symposium on Ada: Ada use in focus : practical lessons in perspective**

Full text available:  [pdf\(559.96 KB\)](#)

Additional Information: [full citation](#), [references](#)

7 Multiprocessor self diagnosis, surgery, and recovery in air terminal traffic control

W. Walther

January 1973 **ACM SIGOPS Operating Systems Review , Proceedings of the fourth ACM symposium on Operating system principles**, Volume 7 Issue 4

Full text available:  [pdf\(533.10 KB\)](#)

Additional Information: [full citation](#), [abstract](#), [index terms](#)

The rapid growth of global aviation for business and pleasure has created the need for automated terminal systems of increasing complexity and capability. Continued increases in the aircraft population will require higher levels of automation. Sperry Univac is responding to this challenge with a multiprocessing system, including hardware and software, currently under development which will enable controllers to safely manage the crowded skies.

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1 Testing and diagnostics of CMOS circuits using light emission from a state leakage current

Stellari, F.; Peilin Song; Tsang, J.C.; McManus, M.K.; Ketchen, M.B.;

Electron Devices, IEEE Transactions on , Volume: 51 , Issue: 9 , Sept. 2004

Pages:1455 - 1462

[\[Abstract\]](#) [\[PDF Full-Text \(1224 KB\)\]](#) **IEEE JNL**

2 TARGET: thermal accelerated reliability go-no-go environmental test dynamic board thermal shock using a single liquid fluorocarbon bath

Beaton, B.P.;

Electronics Manufacturing Technology Symposium, 1991., Eleventh IEEE/CHMT International , 16-18 Sept. 1991

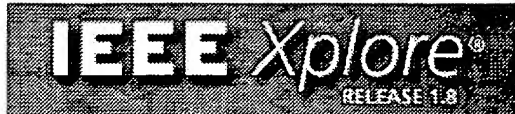
Pages:212 - 214

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debug module

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1 Method of using shadow registers in designing an on-chip debug unit a microprocessor

Chen Bilong; Yan Xiaolang; Wang Jiebing; Xu Zhihan;

ASIC, 2003. Proceedings. 5th International Conference on , Volume: 1 , 21-24 2003

Pages:393 - 396 Vol.1

[Abstract] [PDF Full-Text (340 KB)] IEEE CNF

2 SONICmole: a debugging environment for the UltraSONIC reconfigurable computer

Wiangtong; Ewe, C.T.; Cheung, P.Y.K.;

Circuits and Systems, 2003. ISCAS '03. Proceedings of the 2003 International Symposium on , Volume: 2 , 25-28 May 2003

Pages:II-808 - II-811 vol.2

[Abstract] [PDF Full-Text (404 KB)] IEEE CNF

3 Silicon debug: scan chains alone are not enough

Van Rootselaar, G.J.; Vermeulen, B.;

Test Conference, 1999. Proceedings. International , 28-30 Sept. 1999

Pages:892 - 902

[Abstract] [PDF Full-Text (896 KB)] IEEE CNF

Searching for **PHRASE debug circuit**.

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[Mechanisms for Mixed-Initiative Human-Computer Collaborative.. - Guinn \(1996\) \(Correct\) \(7 citations\)](#)

Stack Initiative: Computer Initiative: Computer **debug**(led,off)observe(switch)Initiative: Computer

Problem-Solving Stack Initiative: Computer **debug**(led,off)Initiative: Computer

In the implemented voice dialogue system "The Circuit Fix-it Shop" Smith et al.1992 Smith and

www.cs.duke.edu/~cig/papers/ACL96.PS

[Mechanisms for Dynamically Changing Initiative in.. - Department \(1996\) \(Correct\) \(2 citations\)](#)

Computer Initiative: Computer goal(fix_circuit)**debug**(led,off)goal(fix_circuit)**debug**(led,off)

debug(led,off)goal(fix_circuit)**debug**(led,off)goal(fix_circuit)**debug**(led,off)

In the implemented voice dialogue system "The Circuit Fix-it Shop" 19]the following dialogue

<ftp.cs.duke.edu/pub/cig/papers/hics.ps.Z>

[Configurable Architecture for System-Level - Prototyping Of High-Speed \(Correct\)](#)

42 4.3.4 In-circuit Debug Environment

Software Tools, Host IDE, MPC8260 ADS 4. In-Circuit Debug environment :JTAG/COP port, In-circuit

platform is completely developed. 4.3.4 In-circuit Debug Environment The MPC8255 processor core has an

scholar.lib.vt.edu/theses/available/etd-07142003-153854/unrestricted/VS_Thesis.pdf

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... by encoding task branch decisions so that the signal processor's **program counter** contents can ... Figure 3 is a block diagram of an on-chip **debug circuit's** debug ...
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... values; and a **debug circuit** (10), wherein the **debug circuit** comprises: a ... a temporary data register 170, a comparator 180, a **Program Counter Breakpoint Mask** ...
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[PDF] [M3A-2114G52/G62/G72 Installation Manual](#)

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... Preexecution PC break The M32R core's internal **debug circuit** (SDI) allows ... before executing an instruction (at the address indicated by the **program counter**). ...
[www.renesas.com/media/products/mpumcu/m32r_family/m32r_ecu_series/child_folder/application_hint/2114im_e.pdf - Similar pages](#)

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... area) CAN Channels Slots Boundary scan On-chip **debug circuit** (SDI) Separate ... purpose registers, five control registers, an accumulator, and a **program counter**. ...
[documentation.renesas.com/eng/ products/mpumcu/rej01b0006_m32recu.pdf - Similar pages](#)

[PDF] [M68ICS08AB](#)

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... One 2 8-pin, 0.1-inch spacing connectors to connect to a remote target via the MON08 **debug circuit** Table 1-1. M68ICS08AB Product Components ...
[rocky.digikey.com/WebLib/ Motorola/Web%20Data/M68ICS08AB.pdf - Supplemental Result - Similar pages](#)

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... The processor status, registers, **program counter**, and so on may then be examined ... hardware breakpoint or debug events, and using active **debug circuit** to control ...
[etd.lib.nsysu.edu.tw/ETD-db/ETD-search/ getfile?URN=etd-0914101-145248&filename=etd-0914101-145248.pdf - Similar pages](#)

[United States Patent Application: 0020144235](#)

... The **debug circuit** itself is composed of a breakpoint detect circuit that is coupled ... bit value that is compared against PC (the value of the **program counter**). ...
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THE REAL-TIME DEBUG OF EMBEDDED SYSTEMS USING DYNAMIC ON-CHIP EMULATIC

The link connects to a dedicated **debug circuit** within the ... emulation is its limited bandwidth, which in essence

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Short Circuit Location - SLIM Samples

for electronic engineers and techs who **debug circuit** boards, manually, and want to find short circuits easily.

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wo-cuts are defined for binary decision diagrams, and the relationship is exhibited between general if-then-else e
 a BDD for the same function. ... information from a sequential **trace** with anonymous semaphore-style ... are coi
 lthough it is ... of which execution generated the **trace**. The main results ...

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 ecution can be misleading, as it implies additional event orderings, distorting ... the ability to simulate and **debug**
 nd with access ...

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